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Application/Control No.	Applicant(s)/Patent under Reexamination
10/666,482	YAMADA ET AL.
Examiner	Art Unit
Erin D. Chiem	2883

SEARCHED			
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385	28-43	4/29/2005	EDC
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH I (INCLUDING SEAR)
	DATE	EXMR
PLUS search	3/14/2005	EDC
forward/backward citation	4/29/2005	EDC
Reviewed IDS	4/27/2005	EDC